

A METHOD OF TESTING A SEQUENTIAL ACCESS MEMORY
PLANE AND A CORRESPONDING SEQUENTIAL ACCESS
MEMORY SEMICONDUCTOR DEVICE

ABSTRACT

The sequential access memory array is able to store p words each of n bits. Such p test words each made up of n test bits are written in the memory array, the p test words are extracted sequentially and, for 5 each current word extracted, the n test bits that compose it are compared sequentially with n respective expected data bits before extracting the next test word.